



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 216491US8		SERIAL NO. 10/080,121	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Tsuyoshi WAKISAKA, et al.			
				FILING DATE February 22, 2002		GROUP 2828	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	EP 0 853 358	7-15-98	European	X		
	AP	JP 10-247757	9-14-98	Japan (with English abstract)			X
	AQ	JP 11-097801	4-9-99	Japan (with English abstract)			X
	AR	DE 4422322	9-14-95	Denmark (with English abstract)			X
	AS	JP 08-335747	12-17-96	Japan (with English Abstract)			X
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Design, Sumulation and Technological Realization of a Reliable Packaging Concept for High Power Laser Bars, Stefan Weiss et al, Electronic Components & Technology Conference, 1988, 48 th IEEE Seattle, WA, May 25-28, 1998, pages 1395-1401					
	AX						
	AY						
	AZ						
Examiner					<input type="checkbox"/> Additional References sheet(s) attached		
Date Considered					8-04		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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SHEET 1 OF 1

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PATENT AND TRADEMARK OFFICE

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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Tsuyoshi WAKISAKA, et al.

FILING DATE

February 22, 2002

GROUP

2812

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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	AM						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	Hai 11-26887	1/29/1999	Japan	X	
	AP	2000-340878	9/8/2000	Japan	X	
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW		
	AX		
	AY		
	AZ		

☐ Additional References sheet(s) attached

Examiner

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